

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

LEE ET AL.

Examiner

Laura S. Weiner

Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR 2001055968	07-2001	Korea	Ahn et al.	
	O				Patent and abstract	
	P	JP 2003157898	05-2003	Japan	Patent, translation and	
	Q				abstract	
	R					
	S					
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**NON-PATENT DOCUMENTS**

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